

Notice of References Cited	Application/Control No. 10/630,855	Applicant(s)/Patent Under Reexamination ODELL ET AL.	
	Examiner Christopher M. Keehan	Art Unit 1712	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,201,945 B1	03-2001	Schlueter et al.	399/329
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	M	US-			

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NON-PATENT DOCUMENTS

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